

# Supporting Information

## Phonon Dispersion Relation of Bulk Boron-Doped Graphitic Carbon

Devin McGlamery<sup>†</sup>, Alexander A. Baker<sup>‡</sup>, Yi-Sheng Liu<sup>||</sup>, Martín A. Mosquera<sup>†</sup>, and Nicholas P. Stadie<sup>†\*</sup>

<sup>†</sup>Department of Chemistry & Biochemistry, Montana State University, Bozeman, Montana, 59717, United States

<sup>‡</sup>Materials Science Division, Lawrence Livermore National Laboratory, Livermore, California, 94550, United States

<sup>||</sup>Advanced Light Source, Lawrence Berkeley National Laboratory, Berkeley, California, 94720, United States

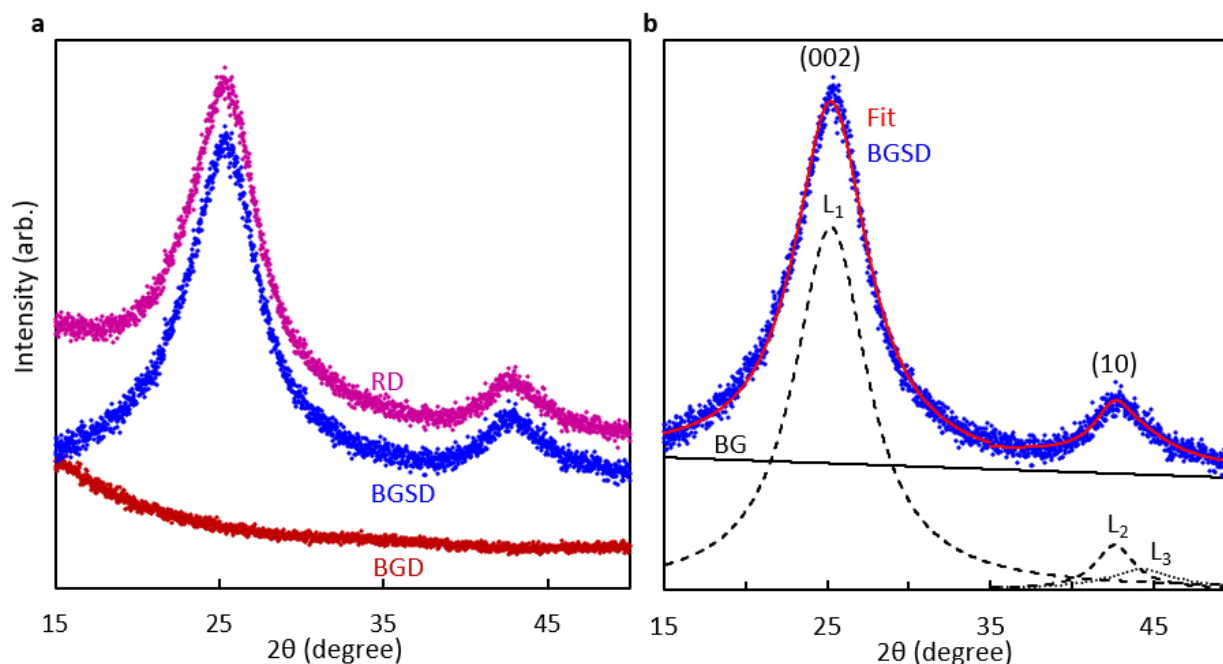
\*Corresponding author: [nstadie@montana.edu](mailto:nstadie@montana.edu)

### Contents:

1.	X-Ray Diffraction	s2
2.	Raman Spectroscopy	s3
3.	X-Ray Absorption Spectroscopy	s5
4.	Energy Dispersive X-Ray Spectroscopy	s6
5.	Auger Electron Spectroscopy	s6
6.	Scanning Electron Microscopy	s8
7.	Phonon Structure Calculations	s9
8.	Supporting References	s12

## 1. X-Ray Diffraction (XRD)

Analysis of the as-measured XRD patterns (RD) was accomplished by direct subtraction of the background (BGD) based on an identical experiment performed without any sample. The resulting pattern (BGSD) was fitted to the combination of a linear background (BG), a single Lorentzian for the (002) reflection (referred to as  $L_1$ ), and two Lorentzians for the (10) region (referred to as  $L_2$  and  $L_3$ ) comprised of the (100) and (101) reflections of crystalline graphite. A representative example is shown in **Figure S1**.



**Figure S1.** XRD pattern analysis. (a) The raw data (RD), measured background data (BGD), and background-subtracted data (BGSD) of  $BC_3'$  synthesized at 800 °C as a representative graphitic carbon material. (b) The BGSD fitted to the combination of a linear background (BG), a single Lorentzian ( $L_1$ ) for the (002) reflection, and two Lorentzians for the (10) family of reflections ( $L_2$  and  $L_3$ ).

The peak center of  $L_1$  was related to the d-spacing via Bragg's law, **Equation 1**, and the full-width at half-maxima (FWHM) of  $L_1$  and  $L_2$  were used to estimate the crystallite size in the c and a axes (referred to as  $L_c$  and  $L_a$ , respectively) via the Scherrer equation, **Equation 2**. The d-spacing and Scherrer size estimates based on the (002) reflection correspond to c-axis (layer-to-layer) ordering whereas the size estimate based on the (10) reflections corresponds to a-axis (in-plane) ordering.<sup>S1</sup>

$$d = \frac{1.54 \text{ \AA}}{2 \sin \theta} \quad (1)$$

$$L = \frac{0.9 \lambda}{(\text{FWHM}) \cos \theta} \quad (2)$$

The FWHM in the Scherrer equation corresponds to the width of the reflection in  $2\theta$ , in radians. When plotting the resulting XRD patterns for comparison (**Figures 1a** and **2a** of the main text), the intensity of each pattern was normalized based on the maximum of the (002) reflection.

## 2. Raman Spectroscopy

The region containing the D and G peaks in each Raman spectrum was fitted using a previously established method based on the combination of a Lorentzian and a Breit-Wigner-Fano (BWF) line shape.<sup>S2</sup> The D peak was fitted to a single Lorentzian (referred to as  $L_4$ ), the G peak was fitted to a single BWF, and the baseline was approximated by a linear background (BG), as shown in **Figure S2a**. The combination of a Lorentzian and a BWF provides a profile with minimal fitting parameters that can effectively fit the Raman spectrum of a wide range of graphitic carbon materials. The BWF line shape is given by **Equation 3**:

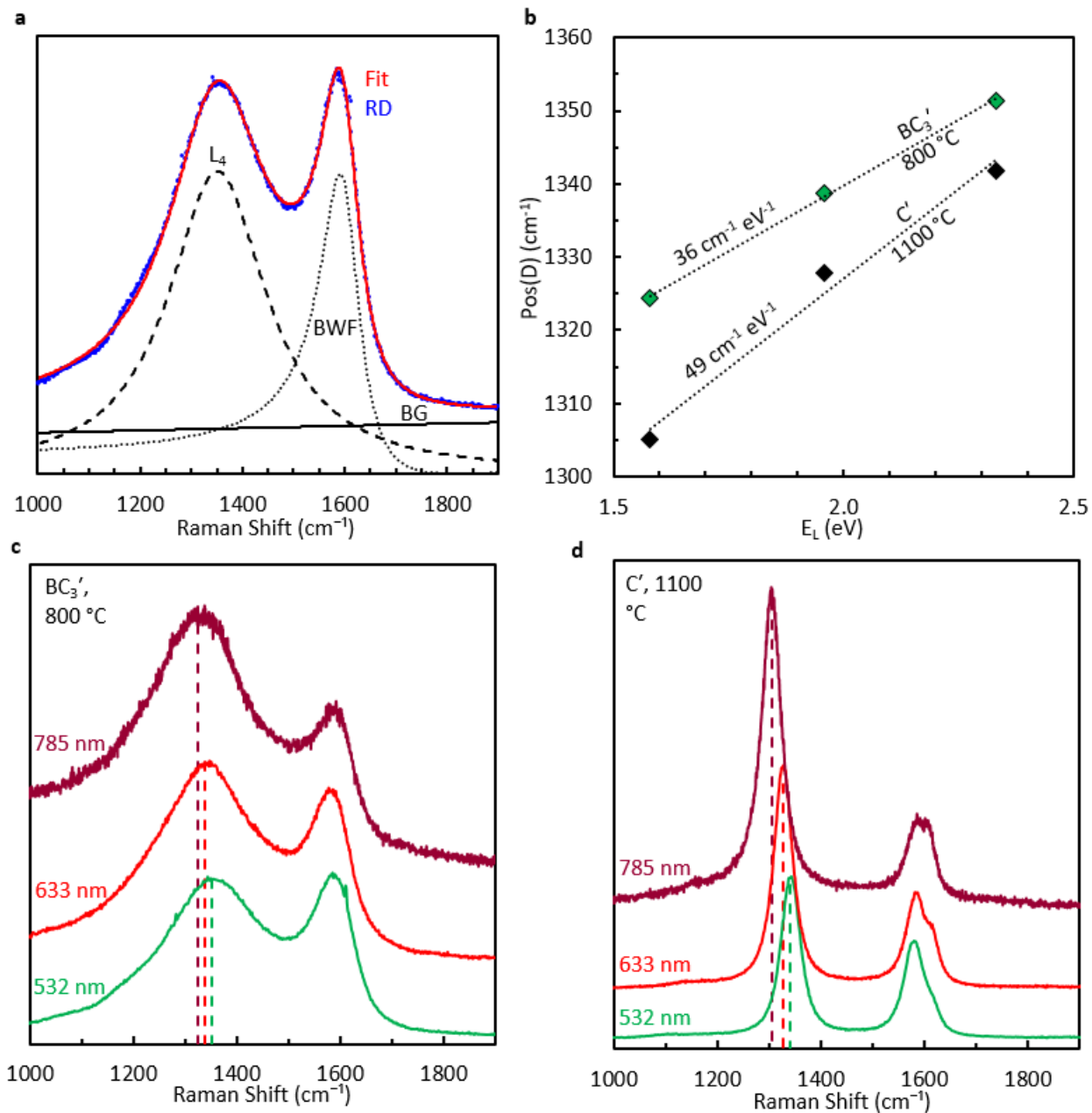
$$I(\omega) = \frac{I_0 [1 + 2(\omega - \omega_0/Q\Gamma)]^2}{1 + [2(\omega - \omega_0/\Gamma)]^2} \quad (3)$$

where  $I_0$  is the peak intensity,  $\omega_0$  is the peak position,  $\Gamma$  is the FWHM, and  $Q$  is the BWF coupling coefficient. A negative  $Q$  value tails the BWF toward lower frequency and accounts for residual intensity between the D and G peaks. Due to the asymmetry of the BWF line shape,  $\omega_0$  does not lie at the frequency of the peak maximum ( $\omega_{\max}$ ) as in a simple Lorentzian or Gaussian function. To correct for this, **Equation 4** was applied to determine  $\omega_{\max}$ . Since  $Q$  is negative,  $\omega_{\max}$  lies at a lower wavenumber than  $\omega_0$ .

$$\omega_{\max} = \omega_0 + \frac{\Gamma}{2Q} \quad (4)$$

$I(D)/I(G)$  was determined for each material based on the ratio of the peak maximum ( $I_0$ ) of  $L_4$  to that of the BWF.  $\text{FWHM}(D)$  and  $\text{FWHM}(G)$  were determined based on  $\Gamma$  of the  $L_4$  and BWF fits, respectively.  $\text{Pos}(D)$  was determined based on  $\omega_0$  of  $L_4$  and  $\text{Pos}(G)$  was determined by applying **Equation 4** to  $\omega_0$  of the BWF fit. The process for determining  $\text{Disp}(D)$  from a set of Raman spectra of varying  $E_L$  is demonstrated in **Figures S2b-d**. In this work, Raman spectra were collected at  $E_L = 532, 633, \text{ and } 785 \text{ nm}$ . The shift in  $\text{Pos}(D)$  as  $E_L$  decreases in energy is shown. The change in  $\text{Pos}(D)$  as a function of  $E_L$  is approximately linear, and the slope of this line is  $\text{Disp}(D)$  in units of  $\text{cm}^{-1} \text{ eV}^{-1}$ .

When plotting the Raman spectra for comparison (**Figures S2c-d** as well as **Figures 1b** and **2b** of the main text), the intensity was normalized based on the maximum of the G peak.

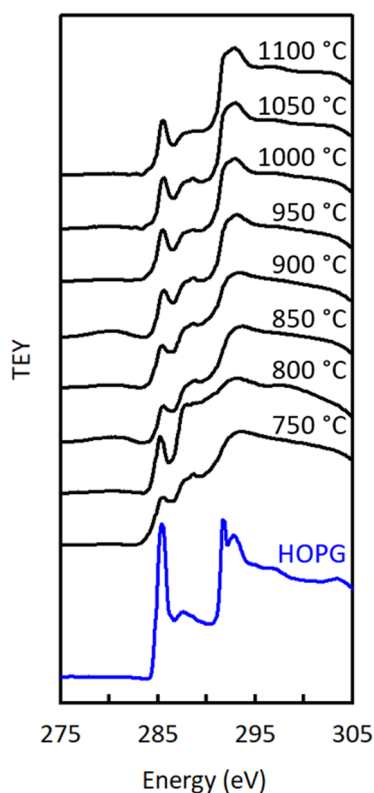


**Figure S2.** Raman spectrum analysis. (a) The raw data (RD) fitted to the combination of a linear background (BG), a single Lorentzian ( $L_4$ ) for the D peak, and a single BWF for the G peak. The Raman spectrum of  $BC_3'$  synthesized at  $800\text{ }^\circ\text{C}$  (analyzed at  $E_L = 532\text{ nm}$ ) is shown as a representative example. (b) The  $E_L$  dependence of  $Pos(D)$  used to calculate  $Disp(D)$  for two materials: (c)  $BC_3'$  synthesized at  $800\text{ }^\circ\text{C}$  and (d)  $C'$  synthesized at  $1100\text{ }^\circ\text{C}$ .

### 3. X-Ray Absorption Spectroscopy (XAS)

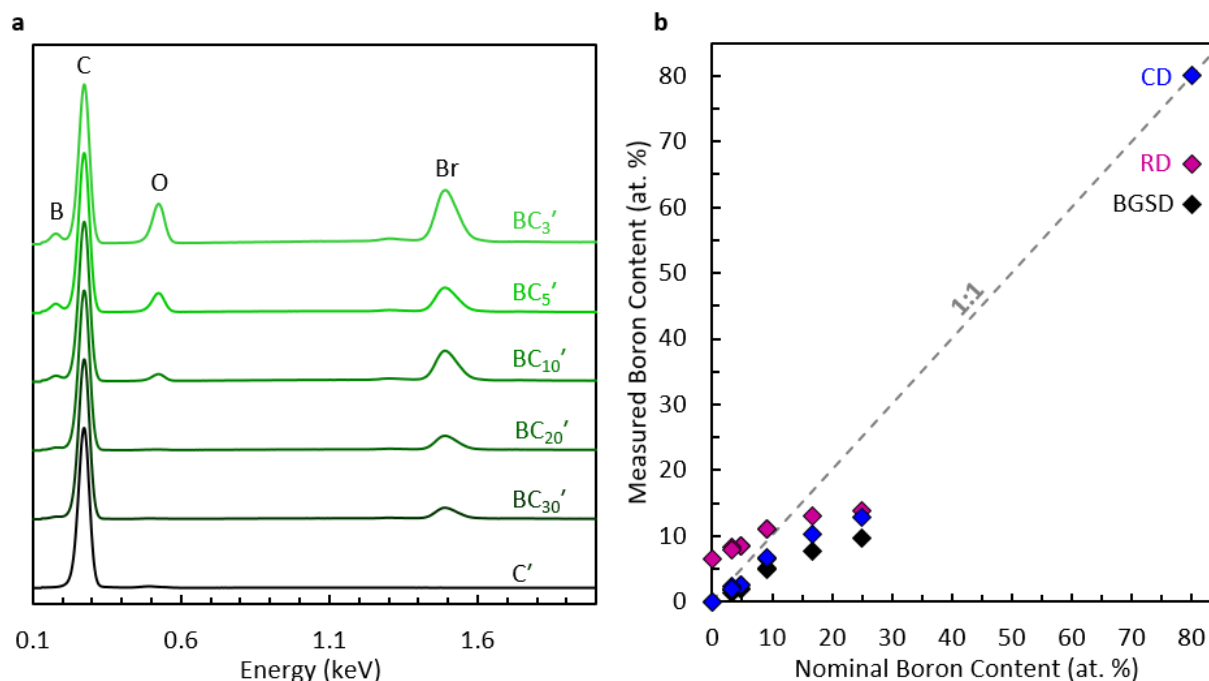
Analysis of the XAS spectra was accomplished by dividing the measured total fluorescence yield (TFY) by the intensity of the incident X-ray beam. This accounts for fluctuations in beam intensity. The corrected spectrum was then normalized based on the pre- and post-edge step height. This provides a physically meaningful comparison between spectra since the pre-edge intensity corresponds to the minimum fluorescence observed and the post-edge intensity results from the excitation of a continuum of states within the bulk material and is expected to be relatively constant. The observed intensities of XAS features should not be directly related to concentrations of specific species within the sample since the scattering cross-sections for different excitations must be considered. As a result, the boron oxide signal observed in all materials investigated is disproportionately large.

The carbon K-edge of the  $BC_3'$  temperature series was also investigated to confirm the graphitic nature of the materials and is shown in **Figure S3**. The development of a strong angle-dependent  $\pi^*$  absorption at 285.5 eV as well as a pronounced  $\sigma^*$  transition at 292 eV shows evidence for ordering of the graphitic structure as synthesis temperature increases.



**Figure S3:** XAS carbon K-edge. Total electron yield (TEY) near the C K-edge of the  $BC_3'$  temperature series (black) compared to HOPG (blue) as a reference.

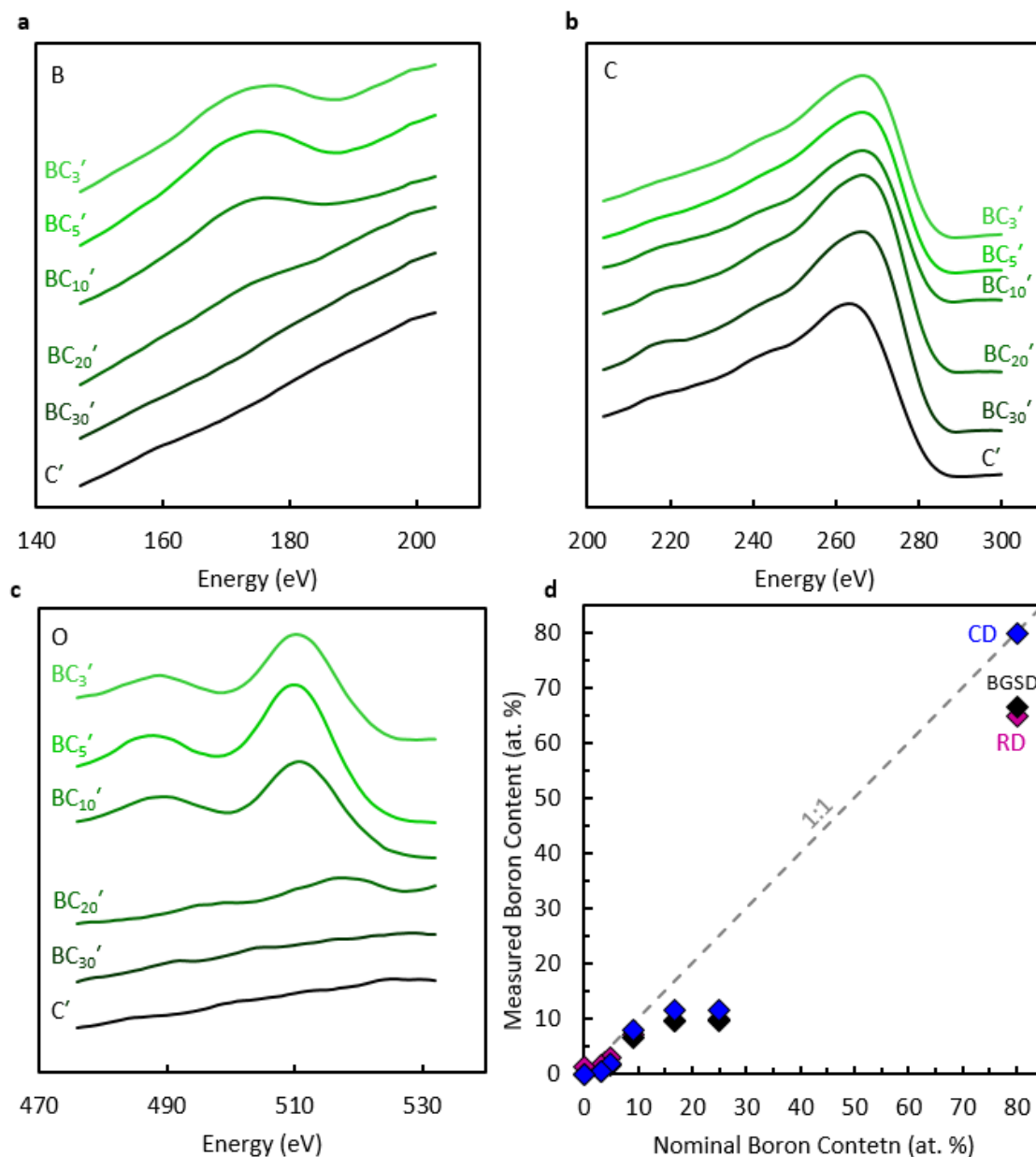
#### 4. Energy Dispersive X-Ray Spectroscopy (EDX)



**Figure S4.** EDX spectrum analysis. (a) EDX spectra of the BC<sub>x</sub>' composition series. (b) The boron content was determined for the BC<sub>x</sub>' composition series as well as a boron carbide standard.

The raw EDX spectra of the BC<sub>x</sub>' composition series are shown in **Figure S4a**. The intensities of the B K $\alpha$  transition as well as the O K $\alpha$  and Br L $\alpha$  transitions increase as a function of nominal boron content. The boron content was determined using sensitivity factors for B, C, O, and Br as implemented by Bruker ESPRIT microanalysis software. As seen in **Figure S4b**, the raw data (RD) overestimate the amount of boron in the material at low compositions; as a result, it is necessary to apply a baseline subtraction (BGSD) to the measured boron content. A correction factor is then applied to the BGSD to bring the measured boron content of the boron carbide (B<sub>4</sub>C) standard up to 80%. The corrected data (CD) show an incorporation limit of boron in carbon at ~11 at. %. The maximum amount of bromine measured in any BC<sub>x</sub>' material was < 0.5 at. %.

## 5. Auger Electron Spectroscopy (AES)

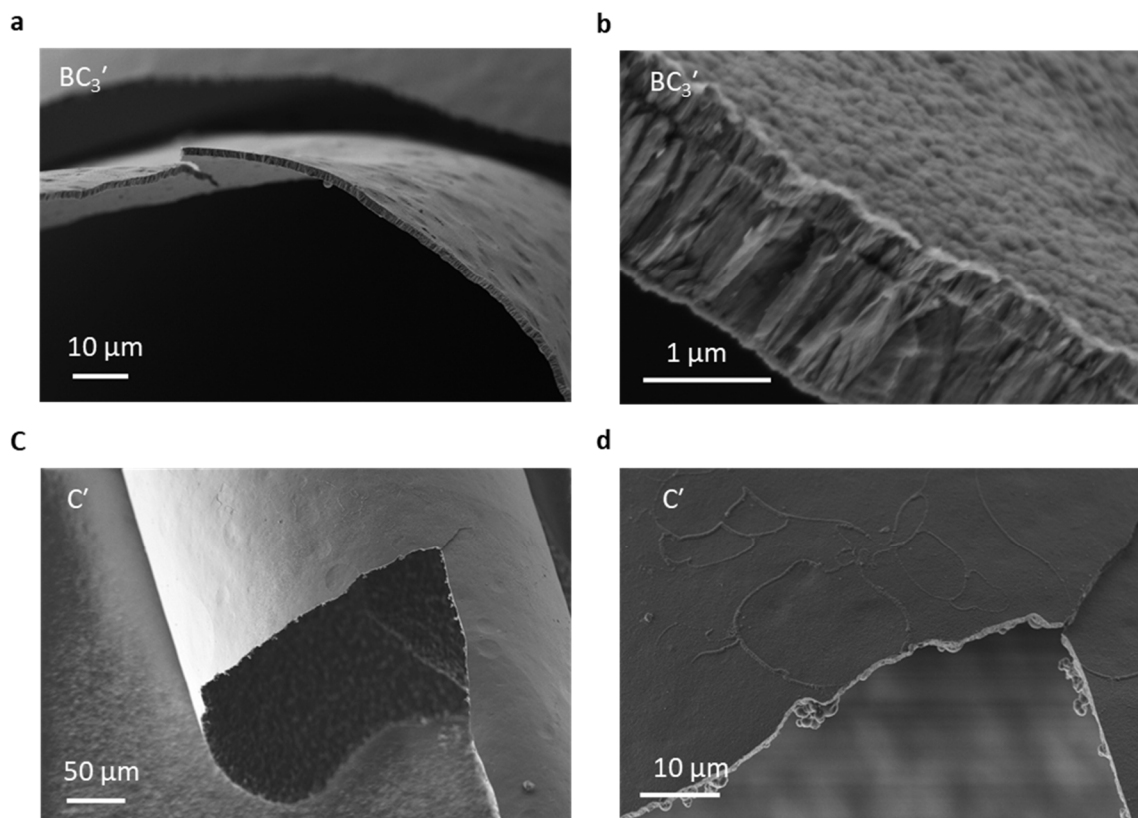


**Figure S5.** AES spectrum analysis. Raw AES spectra for the (a) B K-LL, (b) C K-LL, and (c) O K-LL transitions of the  $BC_x'$  composition series. (b) The boron content was determined for the  $BC_x'$  composition series as well as a boron carbide standard.

Auger electron spectra (AES) of the  $BC_x'$  composition series are shown in **Figures S5a-c**. In qualitative agreement with EDX results, the intensity of the B KLL and O KLL transitions increase with increasing nominal boron content. Quantification of the smoothed and differentiated AES spectra was performed using sensitivity factors as implemented by PHI MultiPak analysis software. The raw data (RD) and background subtracted data (BGSD) are

shown in **Figure S5d**. A correction factor was applied to bring the measured boron content of a boron carbide standard ( $B_4C$ ) up to 80%, shown as corrected data (CD).

## 6. Scanning Electron Microscopy (SEM)

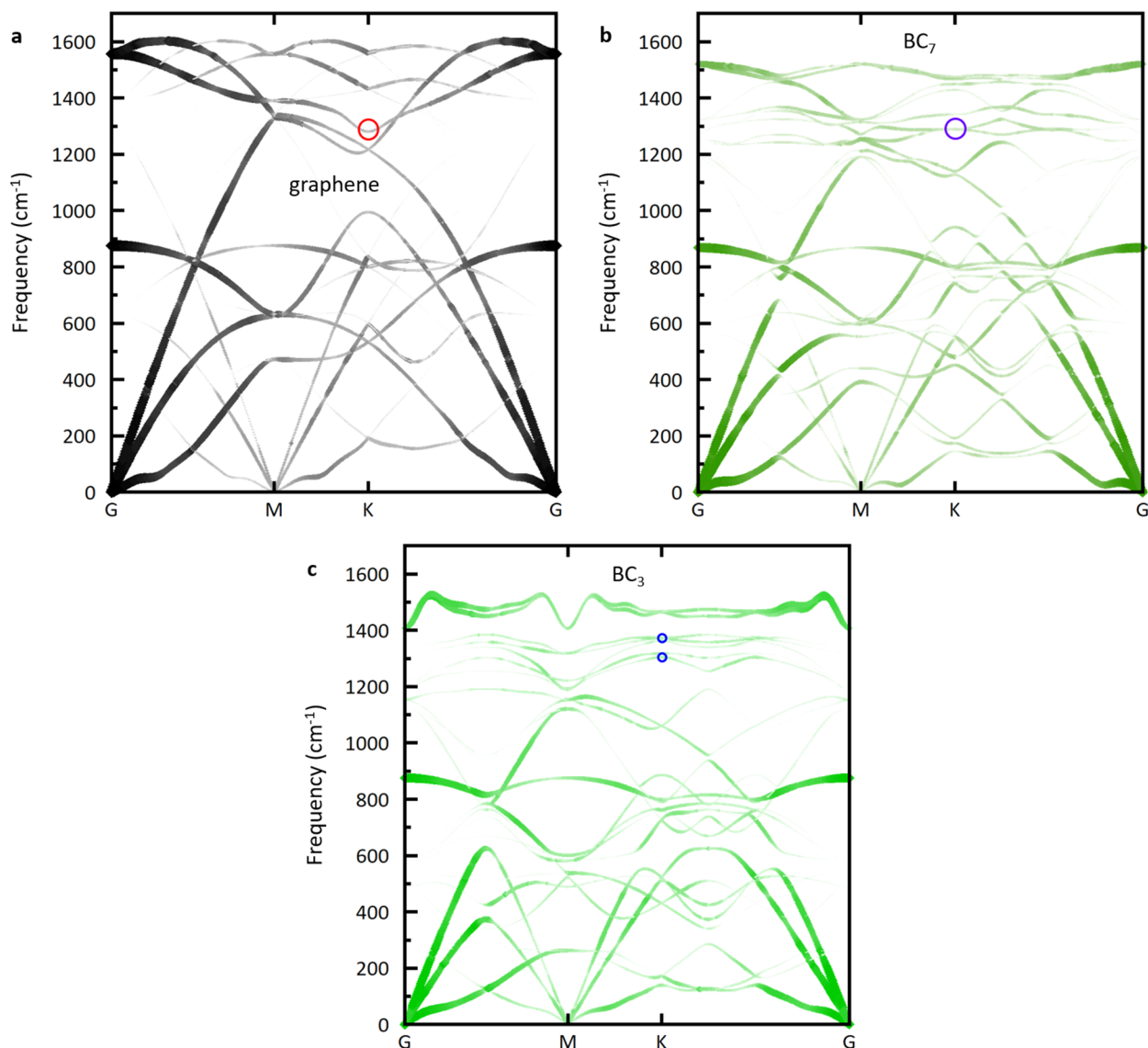


**Figure S6.** Scanning electron microscopy. SEM images of  $BC_3'$  (a) and (b), as well as SEM images of  $C'$  material (c) and (d).

Representative SEM micrographs of  $BC_3'$  and  $C'$  synthesized at 800 °C are shown in **Figure S6**. Two morphologies are observed in both the  $C'$  and  $BC_3'$  materials: flakes up to 1 cm in length and 1-2  $\mu m$  thick, as well as carbonations spheres  $\sim 2 \mu m$  in diameter (seen on the underside of the  $C'$  flake in **Figure S6d**).



## 7. Phonon Dispersion Calculations

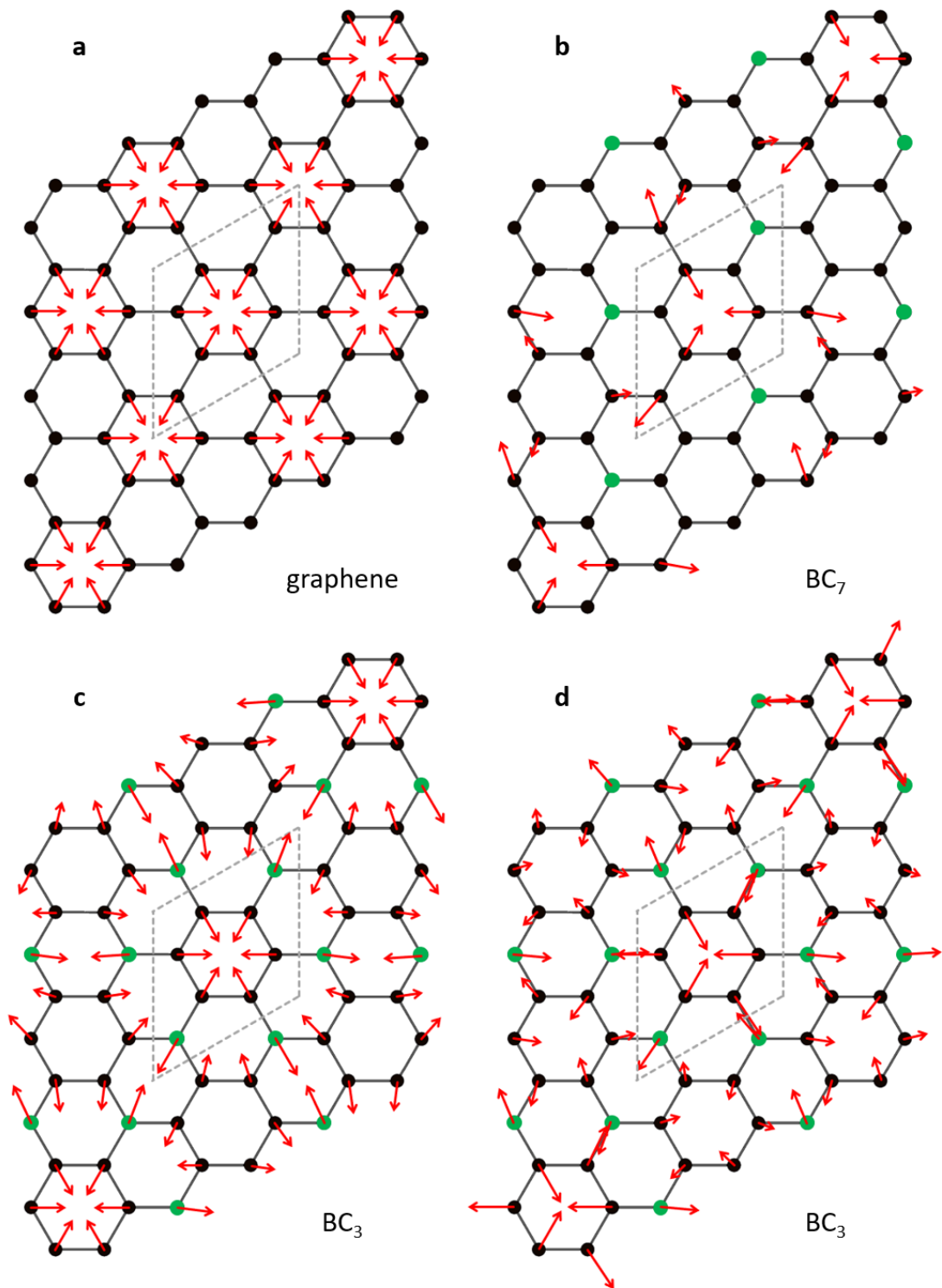


**Figure S7.** Calculated phonon dispersion diagrams for (a) graphene, (b) single-layer BC<sub>7</sub>, and (c) single-layer BC<sub>3</sub>. The optical modes (possibly) contributing to the D peak in the Raman spectrum of BC<sub>x</sub>' are shown in the red, purple, and blue circles, respectively.

The unfolded phonon dispersion diagrams along the high-symmetry directions of the Brillouin zone for graphene, BC<sub>7</sub>, and BC<sub>3</sub>, calculated at the PBE level of DFT, are shown in **Figure S7**. The lattice motion associated with the high frequency TO phonon at the K point is illustrated for four phonons of interest likely to contribute to the D peak in the Raman spectrum of BC<sub>x</sub>' in **Figure S8**. The TO phonon in graphene (red circle, **Figure S7a**), referred to as a "ring breathing" mode, exhibits A<sub>1g</sub> symmetry (**Figure S8a**). The frequency of this phonon is calculated to be 1281 cm<sup>-1</sup> at the K point, but exhibits a distinct Kohn anomaly

and therefore gives rise to a D peak with a strong dispersion relation. We note that the phonon dispersion diagram for graphene was calculated based on a supercell containing 8 atoms, and hence exhibits a number of spurious branches even after unfolding (including some apparent higher optical modes at the K point that are not physically meaningful).

A similar "ring breathing" mode is not present in single-layer BC<sub>7</sub> owing to reduced symmetry; there are no six-membered carbon rings exhibiting bonding environments with hexagonal symmetry. The six-fold axis of symmetry has been replaced by a three-fold axis. The highest symmetry vibrational mode at the K-point in this range of frequency shows breathing-like "ring distortion:" the three carbon-carbon bonds around the three-fold rotational axes elongate, while the three carbon-boron bonds remain stationary (**Figure S8b**). This mode exhibits a frequency of 1289 cm<sup>-1</sup> at the K point (purple circle, **Figure S7b**). Both types of modes appear for single-layer BC<sub>3</sub> owing to the reemergence of six-fold axes of symmetry at the center of each pure carbon ring (blue circles, **Figure S7c**): a "ring breathing" mode at 1363 cm<sup>-1</sup> (**Figure S8c**) and a "ring distorting" mode at 1304 cm<sup>-1</sup> (**Figure S8d**). By symmetry considerations, only the "ring breathing" modes in graphene and BC<sub>3</sub> are truly comparable in their contributions to the position, intensity, and dispersion of the D peak measured in the Raman spectrum of graphitic BC<sub>x</sub>' materials. The "ring breathing" mode at 1363 cm<sup>-1</sup> in BC<sub>3</sub> is flat at near the K point and hence would give rise to a D peak with a negligible dispersion relation.



**Figure S8.** Vibrational modes corresponding to phonon branches of (a) graphene, (b) single-layer  $BC_7$ , and (c-d) single-layer  $BC_3$  at near the measured D peak frequency in graphitic  $BC_x$  materials, at frequencies of 1281, 1289, 1363, and 1304  $\text{cm}^{-1}$ , respectively. Carbon is shown in black, boron in green, and the 8-atom cell used for calculations in gray.

## 8. Supporting References

- S1. Langford, J. I. and Wilson, A. J. C. "Scherrer After Sixty Years: a Survey and Some New Results in the Determination of Crystallite Size." *J. Appl. Crystallogr.* **1978**, 11, 102-113.
- S2. Ferrari, A. C. and Robertson, J. "Interpretation of Raman Spectra of Disordered and Amorphous Carbon." *Phys. Rev. B* **2000**, 61, 14095-14107.